

ABSTRACT:

The invention relates to an arrangement for testing integrated circuits, to a test system (2), to a circuit (1) to be tested, and to a method of testing logic circuits, where the test system (2) includes a programmable algorithmic test vector generator (4) which generates test vectors in real time so as to transfer these vectors to the circuit (1) to be tested.

5

~~Fig. 3~~

1. The first group of people who are interested in the study of the history of the United States are the people who are interested in the history of the United States.